

STP6NK70Z STF6NK70Z

N-CHANNEL 700V - 1.5Ω - 5A TO-220/TO-220FP Zener-Protected SuperMESH™MOSFET

Table 1: General Features

TYPE	V_{DSS}	R _{DS(on)}	I _D	Pw
STP6NK70Z	700 V	< 1.8 Ω	5 A	110 W
STF6NK70Z	700 V	< 1.8 Ω	5 A (*)	30 W

- TYPICAL $R_{DS}(on) = 1.5 \Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
- IMPROVED ESD CAPABILITY
- 100% AVALANCHE RATED
- GATE CHARGE MINIMIZED
- VERY LOW INTRINSIC CAPACITANCES
- VERY GOOD MANUFACTURING REPEATIBILITY

DESCRIPTION

The SuperMESH[™] series is obtained through an extreme optimization of ST's well established stripbased PowerMESH[™] layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOS-FETs including revolutionary MDmesh[™] products.

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- IDEAL FOR OFF-LINE POWER SUPPLIES, ADAPTORS AND PFC

Figure 1: Package

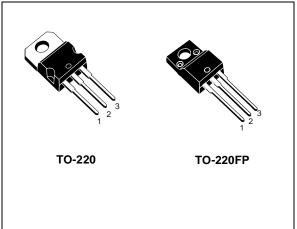


Figure 2: Internal Schematic Diagram

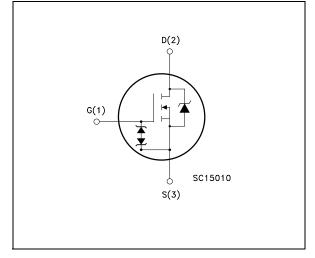


Table 2: Order Codes

SALES TYPE	SALES TYPE MARKING		PACKAGING
STP6NK70Z	P6NK70Z	TO-220	TUBE
STF6NK70Z	STF6NK70Z F6NK70Z		TUBE

Table 3: Absolute Maximum ratings

Symbol	Parameter	Valu	le	Unit
	Γ	STP6NK70Z	STF6NK70Z	
V _{DS}	Drain-source Voltage (V _{GS} = 0)	70	0	V
V _{DGR}	Drain-gate Voltage (R_{GS} = 20 k Ω)	70	0	V
V _{GS}	Gate- source Voltage	± 3	0	V
ID	Drain Current (continuous) at T _C = 25°C	5	5 (*)	А
I _D	Drain Current (continuous) at T _C = 100°C	3.15	3.15 (*)	А
I _{DM} (•)	Drain Current (pulsed)	20	20 (*)	А
Ртот	Total Dissipation at $T_C = 25^{\circ}C$	110	30	W
	Derating Factor	0.87	0.24	W/°C
V _{ESD(G-S)}	Gate source ESD(HBM-C=100pF, R=1.5KΩ)	400	0	V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5		V/ns
VISO	Insulation Withstand Voltage (DC)	-	2500	V
T _j T _{stg}	Operating Junction Temperature Storage Temperature	-55 to 150 -55 to 150		℃ ℃

 (\bullet) Pulse width limited by safe operating area

(1) $I_{SD} \leq 5A$, di/dt $\leq 100A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$.

(*) Limited only by maximum temperature allowed

Table 4: Thermal Data

		TO-220	TO-220FP	
Rthj-case	Thermal Resistance Junction-case Max	1.14	4.2	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5 °C		°C/W
ΤI	Maximum Lead Temperature For Soldering Purpose	300		°C

Table 5: Avalanche Characteristics

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	5	A
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	200	mJ

Table 6: Gate-Source Zener Diode

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
BV _{GSO}	Gate-Source Breakdown Voltage	Igs=± 1mA (Open Drain)	30			V

PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

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ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED) Table 7: On /Off

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 1 mA, V _{GS} = 0	700			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T _C = 125°C			1 50	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 100 \ \mu A$	3	3.75	4.5	V
R _{DS(on}	Static Drain-source On Resistance	V _{GS} = 10 V, I _D = 2.5 A		1.5	1.8	Ω

Table 8: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	V_{DS} = 15 V , I_{D} = 2.5 A		4.4		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0		930 105 22		pF pF pF
C _{OSS eq} (3).	Equivalent Output Capacitance	$V_{GS} = 0 V, V_{DS} = 0 to 560 V$		70		pF
t _{d(on)} t _r t _{d(off)} t _f	Turn-on Delay Time Rise Time Turn-off-Delay Time Fall Time	$\label{eq:VD} \begin{array}{l} V_{DD} = 350 \mbox{ V, } I_D = 2.5 \mbox{ A,} \\ R_G = 4.7 \ \Omega, \ V_{GS} = 10 \ V \\ \mbox{(see Figure 17)} \end{array}$		17 18 45 30		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$\label{eq:VD} \begin{array}{l} V_{DD} = 560 \text{ V}, \text{ I}_{D} = 5 \text{ A}, \\ V_{GS} = 10 \text{ V} \\ \text{(see Figure 20)} \end{array}$		34 6.5 17	47	nC nC nC

Table 9: Source Drain Diode

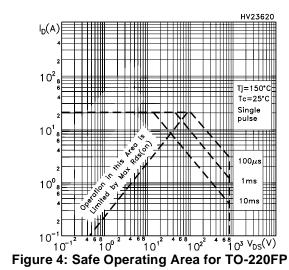
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (2)	Source-drain Current Source-drain Current (pulsed)				5 20	A A
V _{SD} (1)	Forward On Voltage	$I_{SD} = 5 \text{ A}, V_{GS} = 0$			1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I _{SD} = 5 A, di/dt = 100 A/µs V _{DD} = 35V (see Figure 18)		432 2.37 11		ns µC A
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I _{SD} = 5 A, di/dt = 100 A/μs V _{DD} = 35V, T _j = 150°C (see Figure 18)		588 3.38 11.5		ns µC A

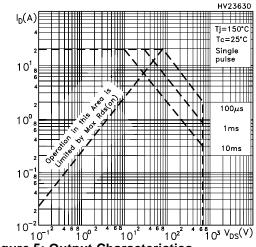
(1) Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %.

(2) Pulse width limited by safe operating area.

(3) Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDS increases from 0 to 80% VDSS.

Figure 3: Safe Operating Area







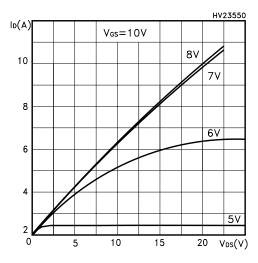


Figure 6: Thermal Impedance

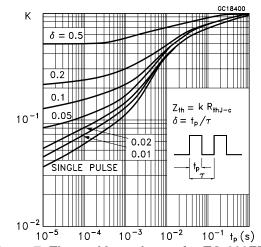


Figure 7: Thermal Impedance for TO-220FP

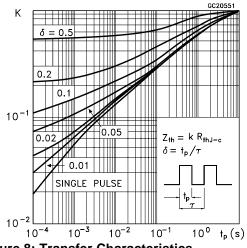
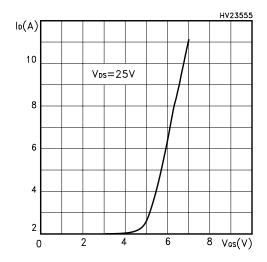


Figure 8: Transfer Characteristics



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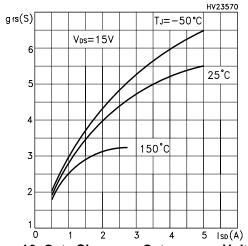


Figure 9: Transconductance

Figure 10: Gate Charge vs Gate-source Voltage

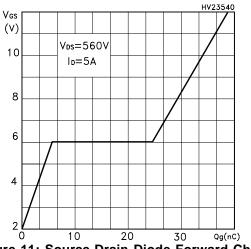
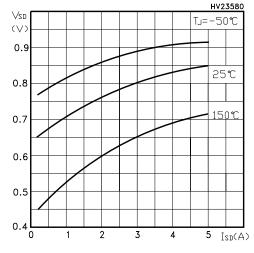


Figure 11: Source-Drain Diode Forward Characteristics



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Figure 12: Static Drain-source On Resistance

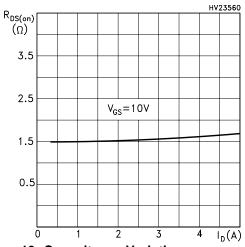


Figure 13: Capacitance Variations

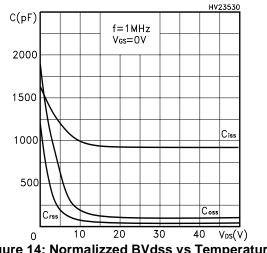
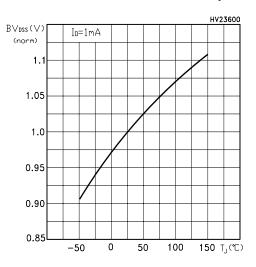


Figure 14: Normalizzed BVdss vs Temperature



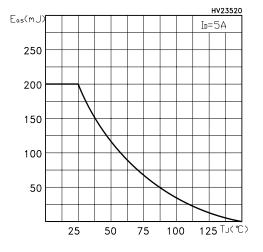


Figure 15: Avalanche Energy vs Starting Tj



Figure 16: Unclamped Inductive Load Test Circuit

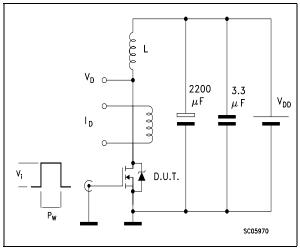


Figure 17: Switching Times Test Circuit For Resistive Load

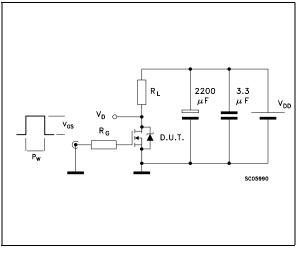


Figure 18: Test Circuit For Inductive Load Switching and Diode Recovery Times

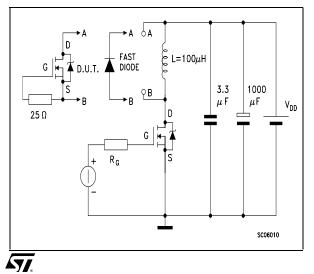


Figure 19: Unclamped Inductive Wafeform

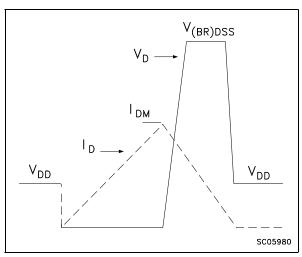
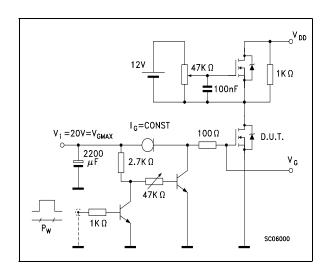


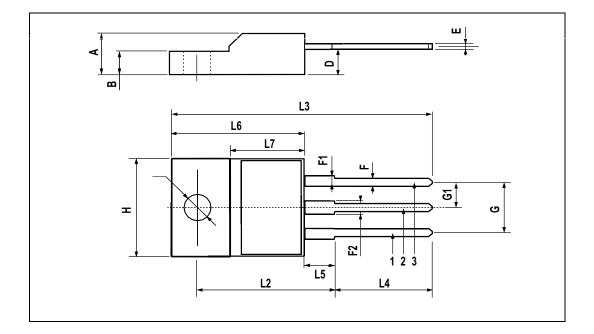
Figure 20: Gate Charge Test Circuit



In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

DIM.	mm.			inch		
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
А	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
Е	0.45		0.7	0.017		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.7	0.045		0.067
F2	1.15		1.7	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	.0385		0.417
L5	2.9		3.6	0.114		0.141
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126

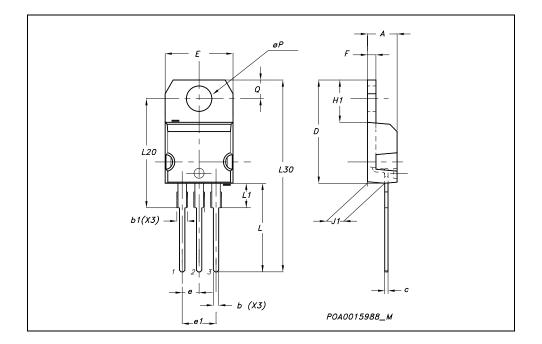




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DIM.		mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
А	4.40		4.60	0.173		0.181	
b	0.61		0.88	0.024		0.034	
b1	1.15		1.70	0.045		0.066	
С	0.49		0.70	0.019		0.027	
D	15.25		15.75	0.60		0.620	
E	10		10.40	0.393		0.409	
е	2.40		2.70	0.094		0.106	
e1	4.95		5.15	0.194		0.202	
F	1.23		1.32	0.048		0.052	
H1	6.20		6.60	0.244		0.256	
J1	2.40		2.72	0.094		0.107	
L	13		14	0.511		0.551	
L1	3.50		3.93	0.137		0.154	
L20		16.40			0.645		
L30		28.90			1.137		
øP	3.75		3.85	0.147		0.151	
Q	2.65		2.95	0.104		0.116	

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Table 10: Revision History

Date	Revision	Description of Changes
24-Sep-2004	1	First release.
04-Nov-2004	2	Complete version
06-Sep-2005	3	Inserted Ecopack indication

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